HiBarSens® NEWSLETTER

HiBarSens® HBS 18-1

SEMPA SYSTEMS®

Valued clients,

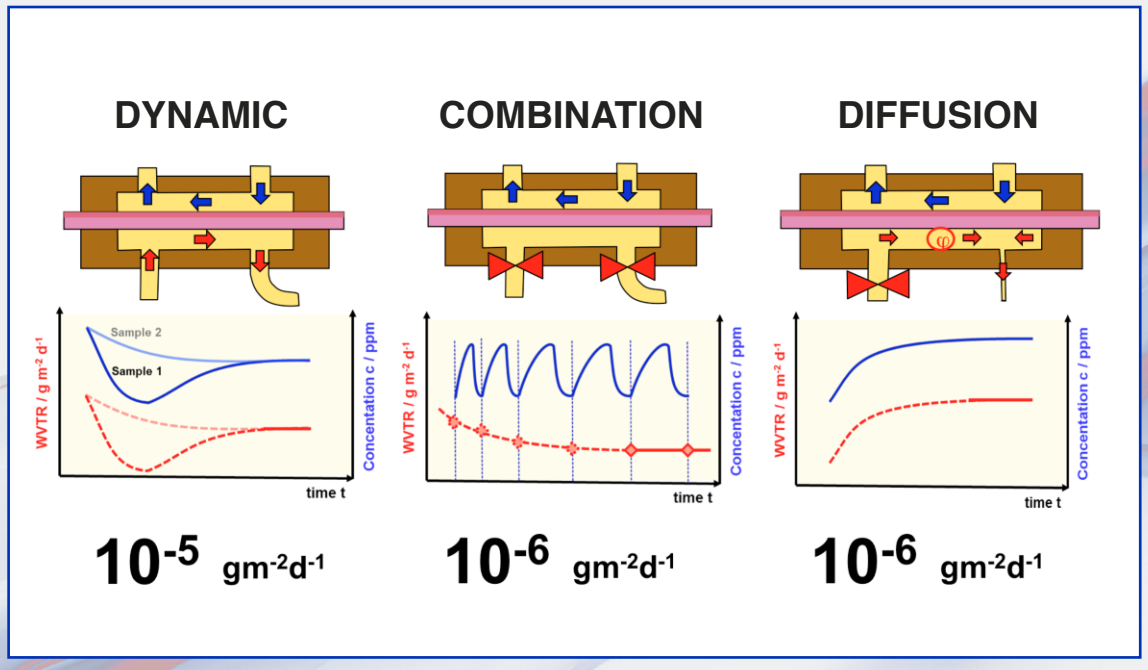
welcome to the 4th edition of the HiBarSens® newsletter. 2013 has been a successful year in launching the upgraded HiBarSens® system, which offers now uniquely three measurement modes. HiBarSens® is also the only commercially available system which measures correctly down to the 10^{-6} g m^{-2} d^{-1} range. Our latest development has been an adapter plate which offers customers the flexibility in measuring smaller samples. Furthermore we are offering cluster solutions for higher throughput.

In 2014 we will present our latest developments at various events and we are looking forward to welcome you personally to our booth at the upcoming exhibitions.

HiBarSens® Technology

One System – Three Measurement modes

HiBarSens® uniquely offers 3 different measurement modes which enable a measurement range between 10^{-6} - 2 g m^{-2} d^{-1}. **DYNAMIC** mode is the standard carrier gas mode which enables the important steady state conditions for the measurement via a slight purge of carrier gas through the measurement chamber. The detection limit of this mode has been pushed down into the high range of 10^{-5} g m^{-2} d^{-1}. The required purge through the measurement cell causes a dilution of the moisture concentration, which limits the detection of this mode.
The newly developed **DIFFUSION** and **COMBINATION** modes innovatively overcome this hurdle as both are decoupling the actual measurement of WVTR from the moisture concentration in the cell.
In our previous issues of this newsletter we have presented those two new modes already in detail and latest measurements really show performance in 10^{-6} g m^{-2} d^{-1} range.



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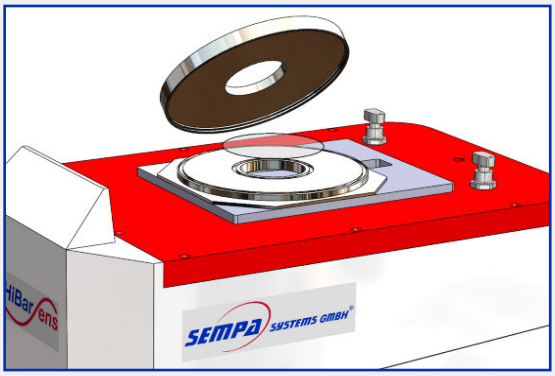
Adpater Plate

Especially in R&D sample diameters can be rather small. With the newly developed adapter plate HiBarSens® addresses this issue as we are now able to measure samples down to a diameter of 85 mm.
The design of the adapter plate also features the important ActiveSeal technology, which enables ambient effect free measurements. Please contact us for further information on this additional feature for the HiBarSens® system.



Meet us at the next upcoming events:

In 2014 the SEMPA HiBarSens® team is present at numerous events globally. Please visit us at the following shows:

Flextech	www.flextech.org	Phoenix/AZ, USA 3.2.2014 - 6.2.2014
Printed Electronics	www.idtechex.com/printed-electronics-europe	Berlin, Germany 1.4.2014 - 2.4.2014
Highly Functional Film	www.filmtech.jp/en	Tokyo Big Sight, Japan 16.4.2014 - 18.4.2014
SEMICON Russia 2014	www.semiconrussia.org/en	Moscow, Russia 14.5.2014 - 15.5.2014
LOPEC	www.lopec.com	Munich, Germany 26.5.2014 - 28.5.2014
ICCG10	www.iccg10.de	Dresden, Germany 22.6.2014 - 26.6.2014
Semicon Taiwan	www.semicontaiwan.org/en	Taipei, Taiwan 3.9.2014 - 5.9.2014
FLEET Workshop Korea		Seoul, South Korea 18.9.2014 - 19.9.2014
CEREBRA Workshop Japan		Osaka, Japan 24.9.2014 - 26.9.2014
Ultra Barrier Workshop		Dresden, Germany 27.11.2014

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